



EMI TEST REPORT

Test Report No. : 28LE0285-HO-B

Applicant : Sharp Corporation, Communication Systems Group.
Type of Equipment : Cellular Phone
Model No. : SH-02A
FCC ID : APYHRO00085
Test regulation : FCC Part 15 Subpart B 2008 Class B
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test: November 11, 2008

Tested by:

T. Shimada

Takumi Shimada
EMC Services

Approved by :

Minoru Yamanaka

Minoru Yamanaka
Assistant Manager of EMC Services



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://uljapan.co.jp/emc/nvlap.html>

UL Japan, Inc.

Head Office EMC Lab.

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MF060b (09.01.08)

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Group.
Address : 2-13-1 Iida Hachihonmatsu, HigashiHiroshima-City, Hiroshima, 739-0192,
Japan
Telephone Number : +81-82-420-1643
Facsimile Number : +81-82-420-1934
Contact Person : Soichi Andoh

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-02A
Serial No. : 004401111560070
Rating : AC 120V/60Hz, DC4.0V
Receipt Date of Sample : November 7, 2008
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: SH-02A (referred to as the EUT in this report) is the Cellular Phone.

Clock frequency(ies) in the system : 48MHz, 390MHz (MAX)

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B 2008, final revised on May 19, 2008
Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 11.7dB, 0.17650MHz, L [AV] 11.4dB, 2.14031MHz, N	Complied
Radiated emission	ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	4.5dB, 70.480MHz, QP Horizontal	Complied

*Note: UL Japan, Inc's EMI Work Procedure QPM05.

*These tests were performed without any deviations from test procedure except for addition or exclusion.

3.3 Additions or deviations to standards

No addition, deviation, nor exclusion has been made from standards.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission	Radiated emission (10m*)			Radiated emission (3m*)			Radiated emission (3m*)	
	150kHz-30MHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz	18GHz-40GHz
No.1 semi-anechoic chamber (±)	3.7dB	3.1dB	4.4dB	4.2dB	3.2dB	3.8dB	3.9dB	5.9dB	6.1dB
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.4dB	4.0dB	5.9dB	6.1dB
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.6dB	4.0dB	5.9dB	6.1dB
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	3.9dB	3.9dB	5.9dB	6.1dB

*10m/3m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
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Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

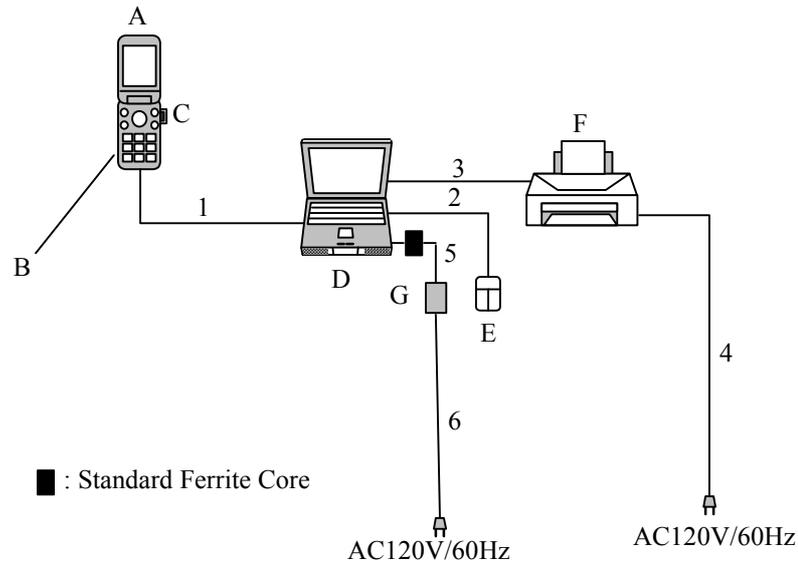
Refer to APPENDIX 1 to 3.

SECTION 4: Operation of E.U.T. during testing

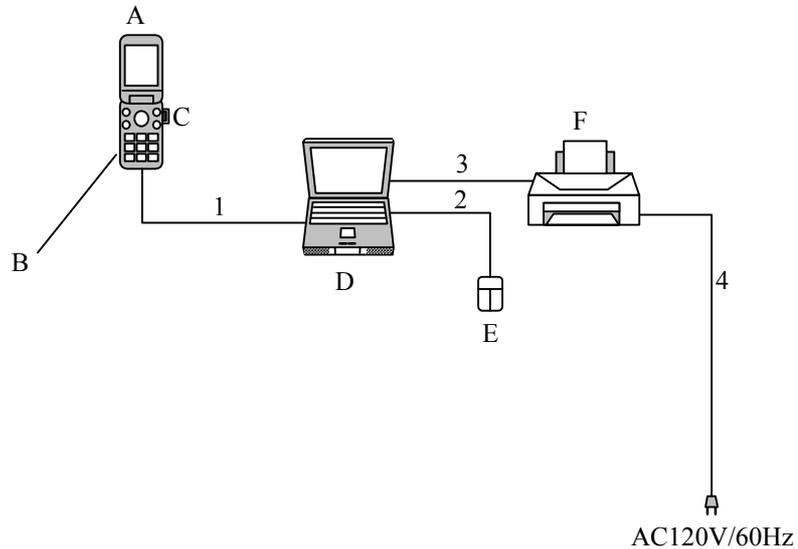
4.1 Operating modes

The mode is used : 1) USB Data Com mode
2) Standby mode

4.2 Configuration and peripherals [Conducted emission test]



[Radiated emission test]



*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

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Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Cellular Phone	SH-02A	004401111560070	SHARP	EUT
B	Lithium-ion Battery	SH20	None	SANYO	EUT
C	microSD Memory Card	SD-C01G	0749R08314V	Toshiba	-
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
E	Mouse	X08-99486	69445-492-0047395-00306	Microsoft	-
F	Printer	PIXUS550i	K10220	Canon	-
G	AC Adapter (Printer)	Canon	K30201	Canon	*1)

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	USB Data Cable	0.75	Shielded	Shielded	-
2	Mouse Cable	1.85	Shielded	Shielded	-
3	Parallel Cable	1.28	Shielded	Shielded	-
4	AC Power Cable (Printer)	1.50	Unshielded	Unshielded	-
5	DC Adapter (PC)	1.85	Unshielded	Unshielded	*1)
6	AC Adapter (PC)	0.90	Unshielded	Unshielded	*1)

*1) Used for Conducted Emission test only

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No.1 semi anechoic chamber.
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 1.

Frequency range : 0.15 MHz-30MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: November 11, 2008

Test engineer: Takumi Shimada

UL Japan, Inc.

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.
Photographs of the set up are shown in Appendix 1.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz -2000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The test was made with the detector (RBW/VBW) in the following table.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 1MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: November 11, 2008

Test engineer: Takumi Shimada

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APPENDIX 1: Photographs of test setup

Conducted Emission

This page has been submitted for a separate exhibit.

Radiated Emission

This page has been submitted for a separate exhibit.

Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)

This page has been submitted for a separate exhibit.

APPENDIX 2: Data of EMI test

Conducted Emission
DATA OF CONDUCTED EMISSION TEST

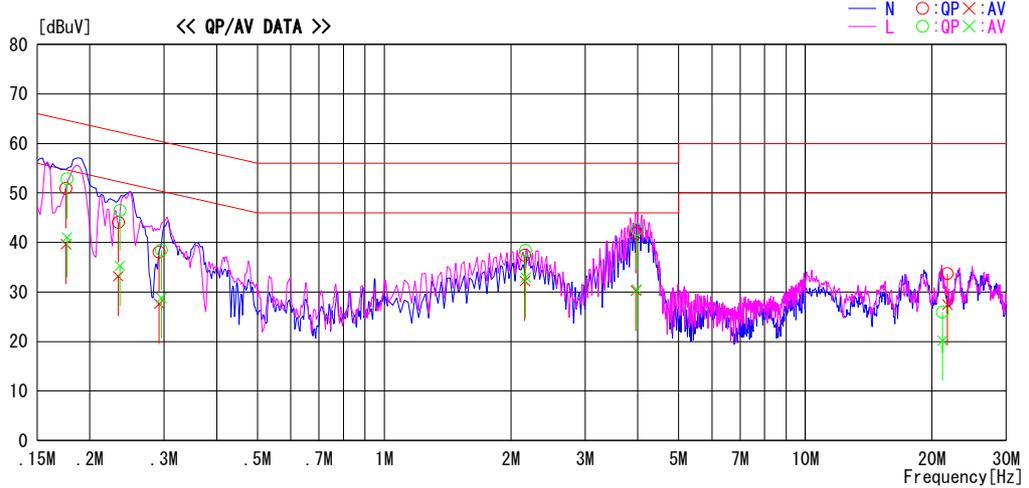
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2008/11/12

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-02A
Serial No. : 004401111560070

Report No. : 28LE0285-HO
Power : AC 120V / 60Hz
Temp./Humi. : 21deg. C / 43%
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP
FCC15.107(a) AV



Frequency [MHz]	Reading Level		Corr. [dB]	Results		Limit		Margin		Phase
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]	
0.17540	50.7	39.5	0.2	50.9	39.7	64.7	54.7	13.8	15.0	N
0.23351	43.7	32.9	0.3	44.0	33.2	62.3	52.3	18.3	19.1	N
0.29208	37.8	27.3	0.3	38.1	27.6	60.5	50.5	22.4	22.9	N
2.15658	36.8	31.6	0.6	37.4	32.2	56.0	46.0	18.6	13.8	N
3.95958	41.1	29.5	0.8	41.9	30.3	56.0	46.0	14.1	15.7	N
21.74330	31.3	25.0	2.4	33.7	27.4	60.0	50.0	26.3	22.6	N
0.17650	52.7	40.9	0.2	52.9	41.1	64.6	54.6	11.7	13.6	L
0.23559	46.2	35.0	0.3	46.5	35.3	62.3	52.3	15.8	17.0	L
0.29558	38.2	28.5	0.3	38.5	28.8	60.4	50.4	21.9	21.6	L
2.16652	37.8	32.3	0.6	38.4	32.9	56.0	46.0	17.6	13.1	L
3.98002	41.8	29.8	0.8	42.6	30.6	56.0	46.0	13.4	15.5	L
21.17505	23.6	17.8	2.4	26.0	20.2	60.0	50.0	34.0	29.8	L

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT[dBuV]=READING[dBuV]+C. F[dB] (L ISN LOSS+CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission DATA OF CONDUCTED EMISSION TEST

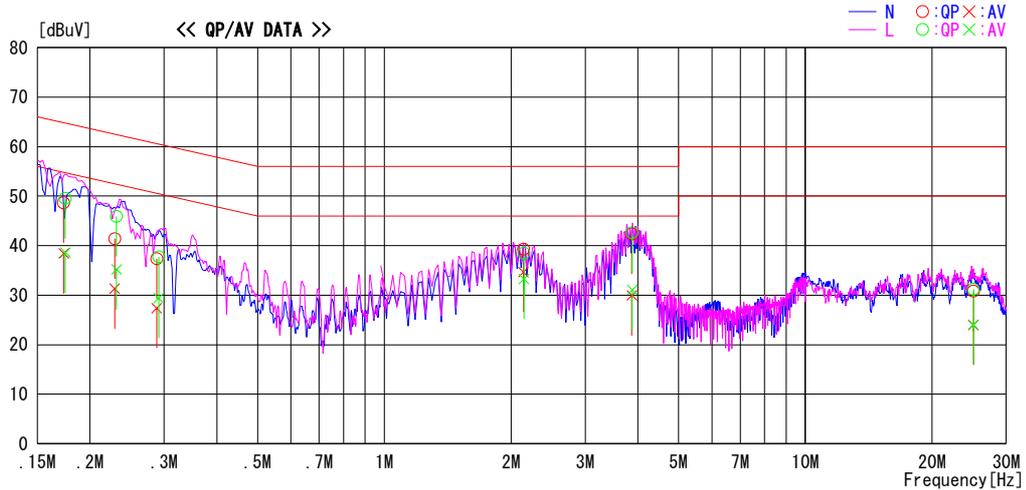
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2008/11/12

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-02A
Serial No. : 004401111560070

Report No. : 28LE0285-HO
Power : AC 120V / 60Hz
Temp./Humi. : 21deg. C / 43%
Engineer : Takumi Shimada

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP
FCC15.107(a) AV



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]	
0.17320	48.5	38.2	0.2	48.7	38.4	64.8	54.8	16.1	16.4	N
0.22900	41.1	31.0	0.3	41.4	31.3	62.5	52.5	21.1	21.2	N
0.28794	37.0	27.1	0.3	37.3	27.4	60.6	50.6	23.3	23.2	N
2.14031	38.8	34.1	0.5	39.3	34.6	56.0	46.0	16.7	11.4	N
3.87351	41.6	29.1	0.8	42.4	29.9	56.0	46.0	13.6	16.1	N
25.06189	28.2	21.4	2.6	30.8	24.0	60.0	50.0	29.2	26.0	N
0.17478	49.3	38.4	0.2	49.5	38.6	64.7	54.7	15.2	16.1	L
0.23128	45.6	34.9	0.3	45.9	35.2	62.4	52.4	16.5	17.2	L
0.29105	37.5	29.1	0.3	37.8	29.4	60.5	50.5	22.7	21.1	L
2.14458	38.0	32.8	0.5	38.5	33.3	56.0	46.0	17.5	12.7	L
3.88061	41.8	30.3	0.8	42.6	31.1	56.0	46.0	13.4	14.9	L
25.07179	28.6	21.4	2.6	31.2	24.0	60.0	50.0	28.8	26.0	L

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT[dBuV]=READING[dBuV]+C.F[dB] (LISN LOSS+CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission

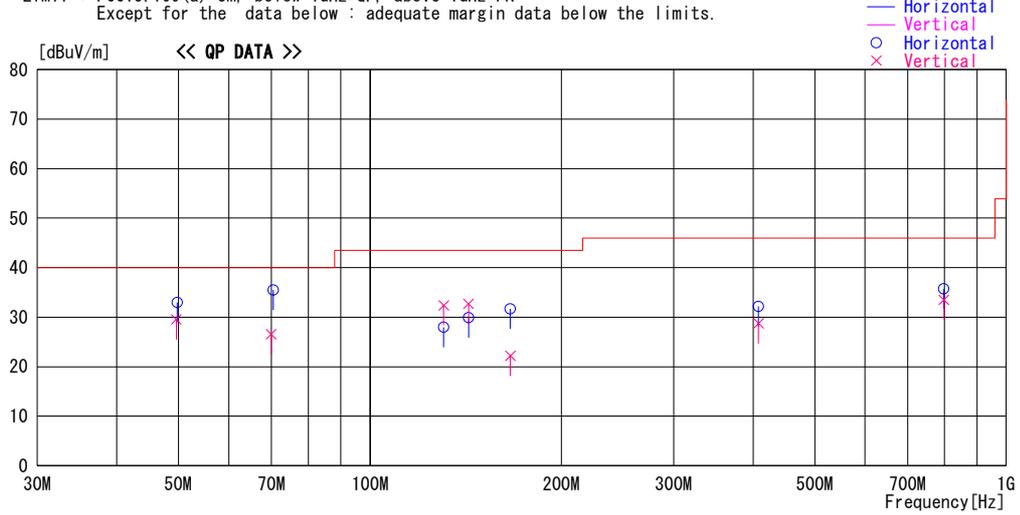
DATA OF RADIATED EMISSION TEST

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Company : Sharp Corporation
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Model No. : SH-02A
Serial No. : 004401111560070
Report No. : 28LE0285-HO
Power : AC 120V / 60Hz
Temp./Humi. : 21deg. C. / 43%
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode, Worst-axis(Hor:X-axis, Ver:X-axis)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin
			Factor	Gain						
			[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]
49.612	40.1	QP	10.3	-20.9	29.5	188	100	Vert.	40.0	10.5
49.776	43.7	QP	10.2	-20.9	33.0	291	300	Hori.	40.0	7.0
69.932	40.2	QP	6.9	-20.5	26.6	246	100	Vert.	40.0	13.4
70.480	49.2	QP	6.8	-20.5	35.5	159	300	Hori.	40.0	4.5
130.540	33.9	QP	13.6	-19.5	28.0	270	300	Hori.	43.5	15.5
130.564	38.3	QP	13.6	-19.5	32.4	209	100	Vert.	43.5	11.1
142.851	37.6	QP	14.5	-19.4	32.7	218	100	Vert.	43.5	10.8
142.853	34.8	QP	14.5	-19.4	29.9	158	122	Hori.	43.5	13.6
166.187	35.0	QP	15.7	-19.0	31.7	344	210	Hori.	43.5	11.8
166.211	25.5	QP	15.7	-19.0	22.2	249	100	Vert.	43.5	21.3
408.001	32.6	QP	16.7	-17.1	32.2	199	100	Hori.	46.0	13.9
408.005	29.1	QP	16.7	-17.1	28.7	152	100	Vert.	46.0	17.3
797.852	29.0	QP	21.7	-15.0	35.7	288	100	Hori.	46.0	10.3
798.121	26.8	QP	21.7	-15.0	33.5	58	100	Vert.	46.0	12.5

CHART: WITH FACTOR ANT TYPE : -30MHz LOOP, 30-300MHz BICONICAL, 300MHz-1000MHz LOGPERIODIC, 1000MHz- HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

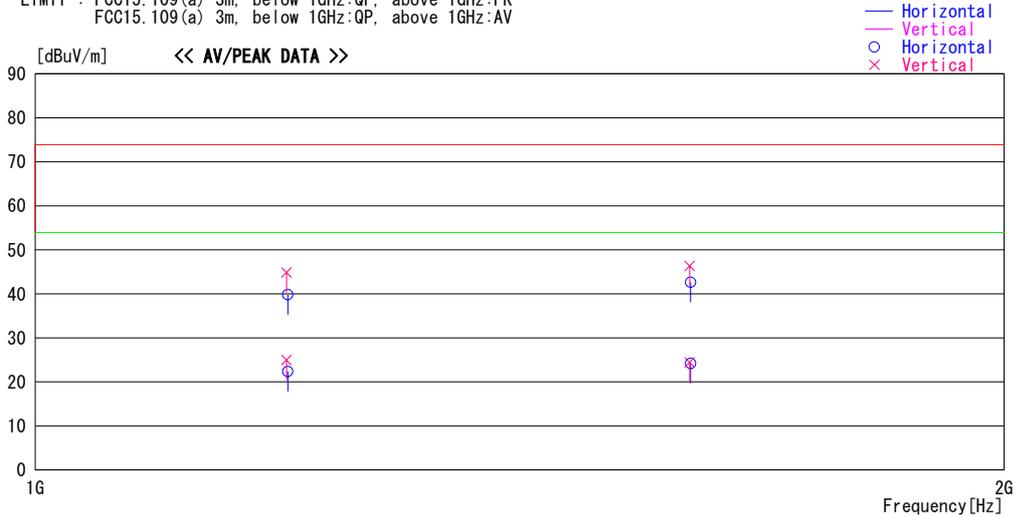
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Serial No. : 004401111560070
Report No. : 28LE0285-H0
Power : AC 120V / 60Hz
Temp./Humi. : 21deg. C. / 43%
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode, Worst-axis(Hor:X-axis, Ver:X-axis)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]
1196.903	55.1	PK	24.7	-34.9	44.9	359	100	Vert.	73.9	29.0
1196.903	35.1	AV	24.7	-34.9	24.9	359	100	Vert.	53.9	29.0
1197.950	50.0	PK	24.7	-34.9	39.8	359	100	Hori.	73.9	34.1
1197.950	32.6	AV	24.7	-34.9	22.4	359	100	Hori.	53.9	31.5
1598.097	33.2	AV	25.3	-34.3	24.2	359	100	Hori.	53.9	29.7
1598.097	51.6	PK	25.3	-34.3	42.6	359	100	Hori.	73.9	31.3
1597.097	55.4	PK	25.3	-34.3	46.4	359	100	Vert.	73.9	27.5
1597.097	33.4	AV	25.3	-34.3	24.4	359	100	Vert.	53.9	29.5

CHART: WITH FACTOR ANT TYPE : -30MHz LOOP, 30-300MHz BICONICAL, 300MHz-1000MHz LOGPERIODIC, 1000MHz- HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 3: Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Anechoic Chamber	TDK	Semi Anechoic Chamber 10m	DA-06881	RE / CE	2008/10/29 * 12
MBA-01	Biconical Antenna	Schwarzbeck	BBA9106	VHA91032007	RE	2008/10/18 * 12
MLA-09	Logperiodic Antenna	Schwarzbeck	USLP9143B	9143B006	RE	2008/10/18 * 12
MAT-02	Attenuator(3dB)	Weinschel Corp	2	BL0968	RE	2007/11/14 * 12
MCC-01	Coaxial Cable 0.1-3000MHz	Suhner/storm/Agilent/ TSJ	-	-	RE	2008/10/02 * 12
MPA-04	Pre Amplifier	Agilent	8447D	2944A09965	RE	2008/07/23 * 12
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE / CE	2008/08/18 * 12
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	100767	RE / CE	2008/06/12 * 12
MSTW-14	EMI measurement program	TSJ	TEPTO-DV	-	RE / CE	-
MOS-01	Digital Humidity Indicator	N.T	NT-1800	MOS01	RE / CE	2007/11/12 * 12
MJM-01	Measure	KDS	ES19-55	-	RE / CE	-
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2008/01/19 * 12
MCC-18	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX 104	233010(1m) / 292410(5m)	RE	2008/09/09 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2008/02/12 * 12
MLS-02	LISN(AMN)	Schwarzbeck	NSLK8127	8127383	CE(EUT)	2008/06/27 * 12
MLS-03	LISN(AMN)	Schwarzbeck	NSLK8127	8127384	CE(AE)	2008/07/01 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/ Agilent/TSJ	-	-	CE	2007/12/27 * 12
MTA-06	Terminator	MCL	BTRM-50	1 9951	CE	2008/02/04 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with traceable calibrations. Each calibration is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted emission

RE: Radiated emission

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